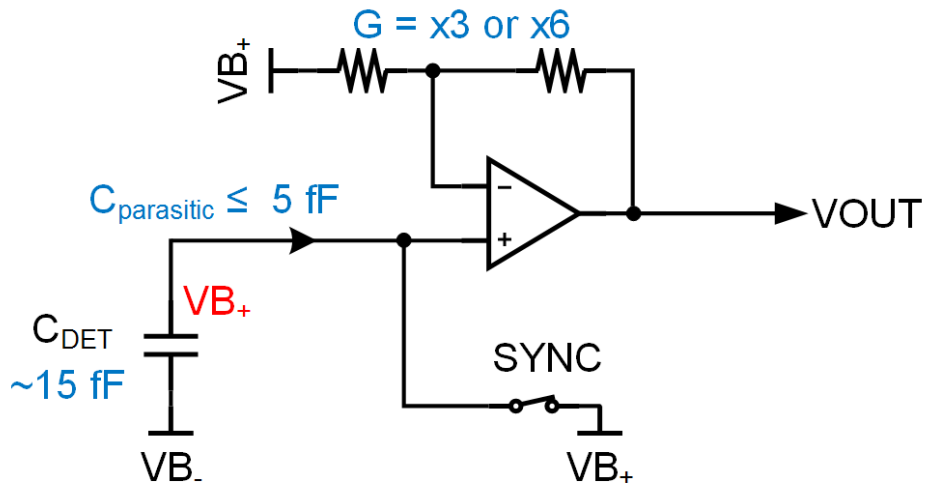


Update

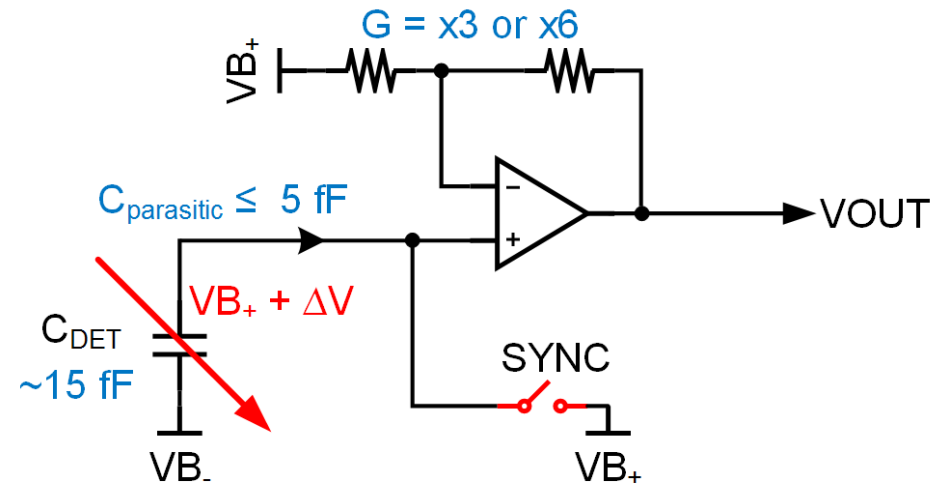
Ray Xu
Apr 14, 2017

- Electrometer OTA (overdue)
 - Operation
 - Specs
- Overview of SEU readout system
- Layout update

SYNC ("RESET") Phase



DETECT Phase



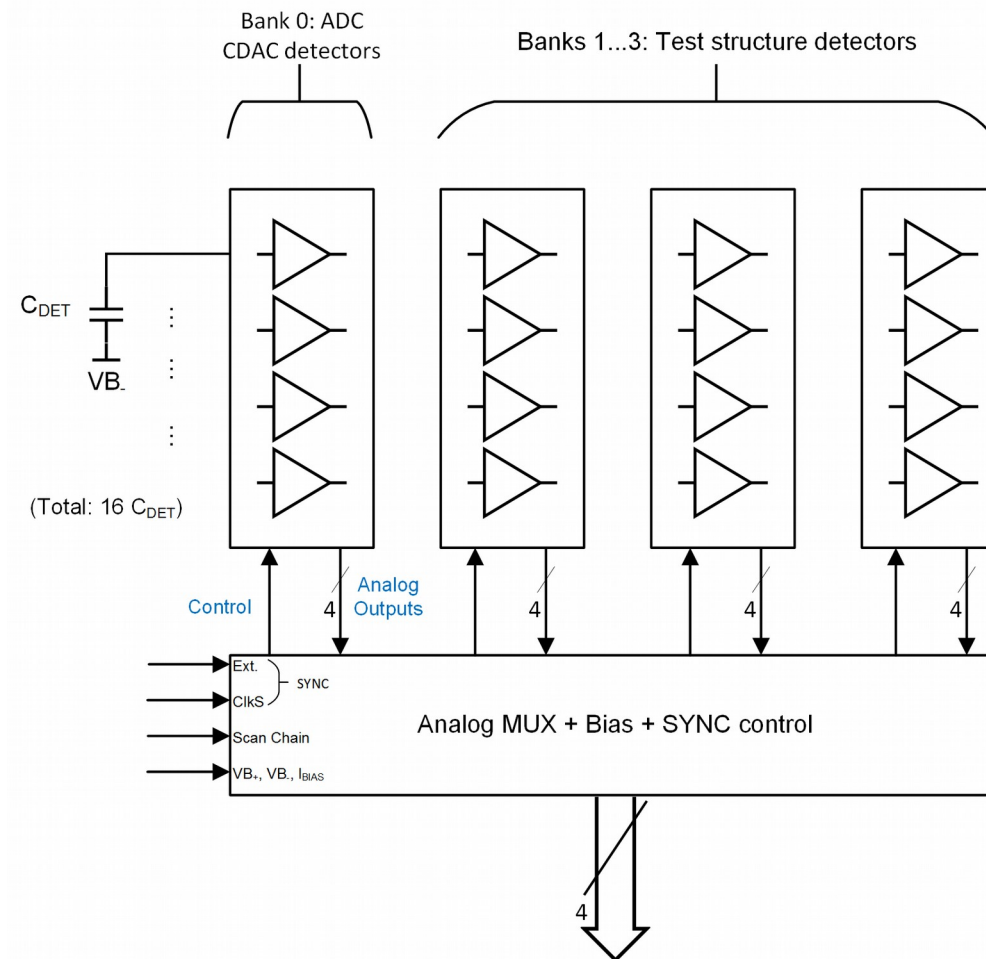
- General
 - 3x or 6x gain (Selected by scan chain)
 - 1 fF input capacitance
 - In. Noise (1 Hz \rightarrow 10 GHz): 2 mVrms
 - Out. Noise (1 Hz \rightarrow 10 GHz): 700uVrms
 - In. Noise (sampled 40MSPS, 1 Hz \rightarrow 20 MHz): 186uVrms
 - Out. Noise (samp. 40MSPS, 1 Hz \rightarrow 20 MHz): 575uVrms
 - (Noise simulated w/ 20pF output load)
 - Low-parasitic & low-charge injection SYNC switch ($\Delta V \sim 20\mu V$)



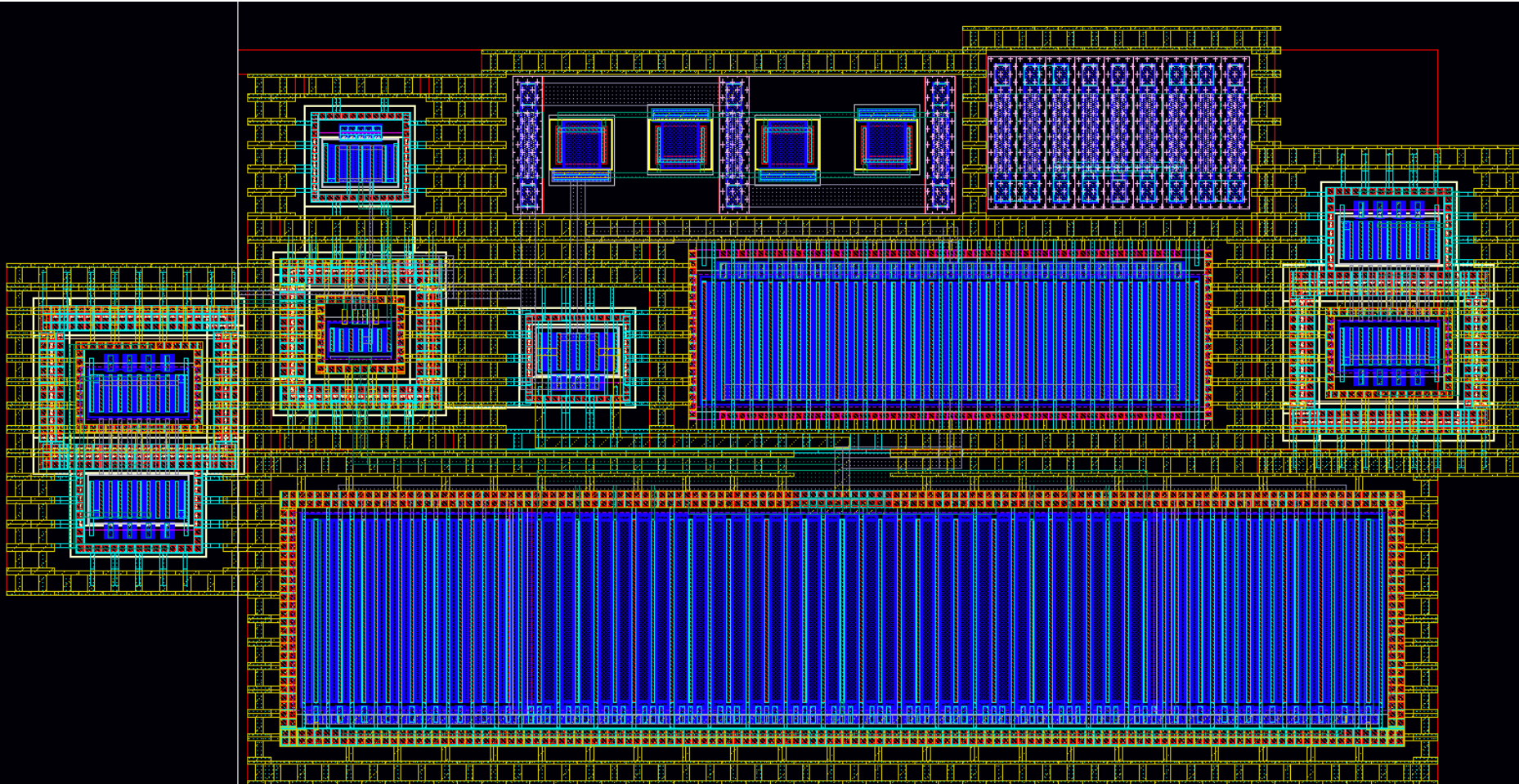
- Post-layout OTA R+C+CC extraction
- 5pF load BW
 - Slow-slow corner
 - $G = \times 3$: 240 MHz, PM 55 deg
 - $G = \times 6$: 137 MHz, PM 50 deg
 - Fast-fast
 - $G = \times 3$: 434 MHz, PM 50 deg
 - $G = \times 6$: 232 MHz, PM 50 deg
- 20pF load BW (only typ-typ corner)
 - $G = \times 3$: 187 MHz, PM 73 deg, 1.5 nS r/f time
 - $G = \times 6$: 116 MHz, PM 63 deg, 2.2 nS r/f time

- Does not use traditional sw-cap integrator
 - Possible to discern between SEU hitting detector cap vs. amplifier circuitry...that's the theory, at least.
 - Compatibility with all capacitances for C_{det}
 - No clocks, latches, or states (all cont. time)
- Caveats: (to be addressed in next tapeout?)
 - 30 dB open-loop gain → possible accuracy issues
 - Voltage offsets per input and across multiple OTA's:
 - Just have one channel/electrometer/OTA in the future?
 - Characterize test chip before irradiation...

- Total power draw: ~5mW
- Additional built-in functionality for testing/characterization purposes



Electrometer Layout



20um x 40um

- Next few days
 - Piece together 4 electrometers (a “Bank”)
 - Start layout on analog MUX + bias distribution + SYNC control (about a dozen unique transistors)
 - CDAC detector cells?